

Search Notes**Application/Control No.**

10/639,052

Examiner

Tadesse Hailu

Applicant(s)/Patent under Reexamination

KATANO, SEIICHI

Art Unit

2173

SEARCHED

Class	Subclass	Date	Examiner
715	744-748	5/3/2007	TH
715	740, 866	5/3/2007	TH
715	738, 736	5/3/2007	TH
715	762-765	5/3/2007	TH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST - Searched all databases (USPAT, PGPUB, IBM-TDB, DERWENT, EPO,&JPO)	5/3/2007	TH
google.com - searched for customization OR customizing "multifunction peripherals" OR multi function peripherals OR MFP ...	5/3/2007	TH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
715	744-748	5/3/2007	TH
715	736, 738	5/3/2007	TH
715	762-765	5/3/2007	TH
PGPUB - CLM searched - search history enclosed		5/3/2007	th